



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L ULTW 16.0003-09	Issue No.:	4	Status:	Current
Additional Site to Certification: IECQ-L ULTW 16.0003		Originally Issued: 2016/07/28			
Supersedes:	IECQ-L ULTW 16.0003-09 Issue 3	Issue Date:	2025/06/25	Site Added:	2021/09/04
CB Reference No.:	50600421 ITL	Expiration:	2028/07/27		

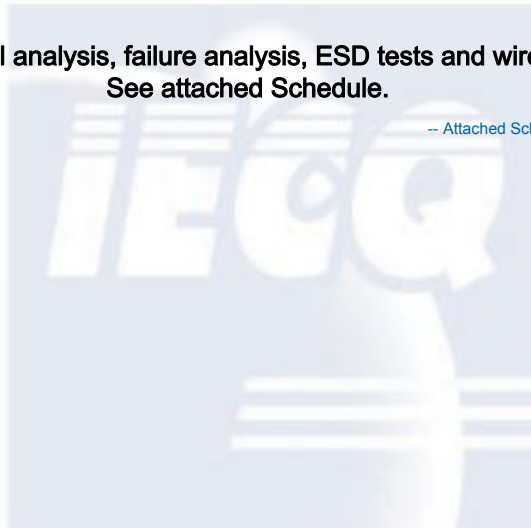
Materials Analysis Technology Inc.
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 Taiwan

The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

The materials analysis, chemical analysis, failure analysis, ESD tests and wire bonding of semiconductors.
 See attached Schedule.

-- Attached Schedule: IECQ-L_ULTW_50600421 ITL, 06-25-25.pdf --



Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road,
 Feng Yuan Dist., Taichung City
 Taiwan

Authorized person:
Bob CHEN



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.
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**Schedule of Scope to Certificate of Approval
Independent Testing Laboratory**

IECQ Certificate No.: IECQ-L ULTW 16.0003-09

CB Certificate No.: 50600421 ITL

Schedule Number: IECQ-L ULTW 16.0003-09-S Rev No.: 4 Revision Date: 2025/06/25 Page 1 of 1

Appendix-1 (50600421 ITL)

Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
Emission Microscopy (EMMI)	T-EFA-3
Emission Microscopy (EMMI)-InGaAs	T-EFA-3
Optical Beam Induced Resistance Change (OBIRCH)	T-EFA-3
Thermal Emission Microscope (THEMOS)	T-EFA-3
3D X-Ray microscopy	T-EFA-3
3D Optical Microscope (3D OM)	T-LAB-3
Human Body Mode (HBM)	ANSI/ESDA/JEDEC JS-001, ANSI/ESD STM 5.1, JESD22-A114, MIL-STD-883, AEC-Q100-002
Machine Mode (MM)	ANSI/ESD S5.2, JESD22-A115, AEC-Q100-003
Charge Device Mode (CDM)	ANSI/ESD S5.3.2, ANSI/ESD S5.3.1, JESD22-C101, ANSI/ESDA/JEDEC JS-002, AEC-Q100-011
Wire Bonding	T-EFA-3
X-Ray imaging	T-EFA-3
Latch-up test	JESD78, AEC Q100-004
Transmission Line Pulse (TLP)	ANSI/ESD STM5.5.1
Electrical Overstress (EOS)	IEC 61000-4-5

Technical Reviewer of DQS: Paul Yang Date: 6/25/2025

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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

